

Applicant: Koichi Takiguchi, et al.

Confirmation No.: 7656

Serial No.: 10/614,637

Att'y Docket No.: 14321.55

Filing Date: 07/07/2003

Group: 2874

For: CHARACTERISTIC ADJUSTMENT METHOD OF MULTISTAGE MACH-ZEHNDER INTERFEROMETER TYPE OPTICAL CIRCUIT

INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

Examiner Initial*	Document Number	Issue Date	Name
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Foreign Patent Documents

Examiner Initial*	Document Number	Publication Date	Country or Patent Office	Translation
<u>SP</u> 1	JP 7209090	11/08/1995	Japan	Abstract only

Other Documents

(including author, title, pertinent pages, etc.)

Examiner
Initial*

<u>SP</u> 2	OFFREIN, B. J., et al., "Adaptive Gain Equalizer in High-Index-Contrast SiON Technology," <i>IEEE Photonics Technology Letters</i> , IEEE Inc., New York, US, Vol. 12, No. 5, May 2000, pp. 504-506
<u>SP</u> 3	WACOGNE, B., et al., "Double Security Level in a Telecommunication System Based on Phase Coding and False Data Transmission," <i>Journal of Lightwave Technology</i> , IEEE, New York, US, Vol. 14, No. 5, May 1996, pp. 665-670
<u>SP</u> 4	TAKIGUCHI, K., et al., "Variable Group-Delay Dispersion Equalizer Using Lattice-Form Programmable Optical Filter on Planar Lightwave Circuit," <i>IEEE Journal of Selected Topics in Quantum Electronics</i> , IEEE Service Center, US, Vol. 2, No. 2, June 1996, pp. 270-276
<u>SP</u> 5	TAKADA, K., et al., "Measurement of phase error distributions in silica-based arrayed-waveguide grating multiplexers by using Fourier transform spectroscopy," <i>Electronic Letters</i> , IEE Stevenage, GB, Vol. 30, No. 20, 29 September 1994, pp. 1671-1672

Examiner:

Sung Park

Date Considered:

2/18/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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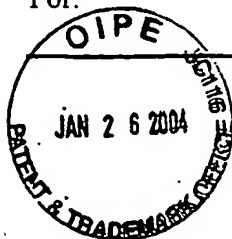
Serial No.: 10/614,637

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Filing Date: July 7, 2003

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<u>HL</u> 1	5,596,661	01/21/1997	Henry et al.

Foreign Patent Documents

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Other Documents

(including author, title; pertinent pages, etc.)

<u>Examiner Initial*</u>	
<u>HL</u> 2	Koichi Takiguchi et al., <i>Planar Lightwave Circuit Optical Dispersion Equalizer</i> , IEEE Photonics Technology Letters, Vol. 6, No. 1, January 1994, pp. 86-88.
<u>SL</u> 3	S. Suzuki et al., <i>Low-Loss Integrated-Optic Dynamic Chromatic Dispersion Compensators Using Lattice-Form Planar Lightwave Circuits</i> , Tuesday Afternoon, Vol. 1, OFC 2003, pp. 176-177.
<u>HL</u> 4	K. Takiguchi et al., <i>Method for Adjusting Lattice-Form Optical Devices and Its Use in Realising Low-Loss Variable Chromatic Dispersion Compensator</i> , Electronics Letters, Vol. 39, No. 4, February 20, 2003.

Examiner: Sunny ParkDate Considered: 2/18/05

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Form PTO-1449

Sheet 2 of 2

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